# Phasing with electronic radiation damage at high x-ray intensity

#### Sang-Kil Son

Center for Free-Electron Laser Science, DESY, Hamburg, Germany

BioXFEL 2nd International Conference Ponce, Puerto Rico / January 14–16, 2015





**Center for Free-Electron Laser Science** 

CFEL is a scientific cooperation of the three organizations: DESY – Max Planck Society – University of Hamburg





## Collaboration

#### **CFEL-DESY** Theory Division



**Robin Santra** 

#### **CFEL Coherent Imaging Division**



Henry Chapman



Lorenzo Galli





# **Phasing for XFEL experiments**

- > Phase problem: a fundamental obstacle in obtaining a structure from x-ray diffraction
- Mainly solved by molecular replacement e.g.) Redecke et al., Science 339, 227 (2013).
- SAD in the intermediate intensity regime Barends et al., Nature 505, 244 (2014).
- Need for ab initio phasing method at high x-ray intensity



Cathepsin B: The first new protein structure determined by using XFEL

Picture taken from Nature 505, 620 (2014).





## **Electronic radiation damage**

- > Unavoidable at high x-ray intensity (time scale: ~femtoseconds)
- > Can we reduce electronic radiation damage?
  - much shorter pulse duration, less ionization (frustrated ionization)
  - narrower bandwidth, less ionization (resonance-enabled ionization)
- Can we take benefits from electronic radiation damage?
  - understand ionization dynamics mechanism
  - turn x-ray multiple ionization into an advantage for phasing





# Sequential multiphoton multiple ionization



- described by sequences of photoionization, Auger, and fluorescence
- complex inner-shell ionization dynamics (>2B x-ray-induced processes)





# **XATOM:** all about x-ray atomic physics

- Computer program suite to describe dynamical behaviors of atoms interacting with XFEL pulses
- > Uses the Hartree-Fock-Slater model
- Calculates all cross sections and rates of x-ray-induced processes for any given element
- Solves coupled rate equations to simulate ionization dynamics
- Calculates ion / electron / photon spectra, directly comparable with XFEL experiments



Son, Young & Santra, *Phys. Rev. A* **83**, 033402 (2011).





## Charge-state distribution: EXP vs. theory



## **MAD with XFEL**

- MAD (multiwavelength anomalous diffraction): employing the dispersion correction of x-ray scattering from heavy atoms
- Can we use MAD with XFEL?
  - Unavoidable electronic radiation damage, especially to heavy atoms
  - Dramatic change of anomalous scattering for high charge states
  - Stochastic ionization nature destroying coherent signals
- Need to understand dynamic behaviors of individual atoms



## **Generalized Karle-Hendrickson equation**

Scattering intensity including ionization dynamics of heavy atoms

$$\frac{dI(\mathbf{Q},\mathcal{F},\omega)}{d\Omega} = \mathcal{F}C(\Omega) \int_{-\infty}^{\infty} dt \, g(t) \sum_{I} P_{I}(\mathcal{F},\omega,t) \left| F_{P}^{0}(\mathbf{Q}) + \sum_{j=1}^{N_{H}} f_{I_{j}}(\mathbf{Q},\omega) e^{i\mathbf{Q}\cdot\mathbf{R}_{j}} \right|^{2}$$

 $\begin{aligned} \frac{dI(\mathbf{Q}, \mathcal{F}, \omega)}{d\Omega} &= \mathcal{F}C(\Omega) \Big[ \big| F_P^0(\mathbf{Q}) \big|^2 + \big| F_H^0(\mathbf{Q}) \big|^2 \tilde{a}(\mathbf{Q}, \mathcal{F}, \omega) \\ &+ \big| F_P^0(\mathbf{Q}) \big| \big| F_H^0(\mathbf{Q}) \big| b(\mathbf{Q}, \mathcal{F}, \omega) \cos \Delta \phi^0(\mathbf{Q}) \\ &+ \big| F_P^0(\mathbf{Q}) \big| \big| F_H^0(\mathbf{Q}) \big| c(\mathbf{Q}, \mathcal{F}, \omega) \sin \Delta \phi^0(\mathbf{Q}) \\ &+ N_H \big| f_H^0(\mathbf{Q}) \big|^2 \left\{ a(\mathbf{Q}, \mathcal{F}, \omega) - \tilde{a}(\mathbf{Q}, \mathcal{F}, \omega) \right\} \Big] \end{aligned}$ 

MAD coeff: measured or calculated / 3 unknowns: solvable with 3 measurements

Son, Chapman & Santra, Phys. Rev. Lett. 107, 218102 (2011).





12

# MAD coeff. including ionization dynamics

Time-dependent form factor: dynamically synchronized for all heavy atoms -> contributing coherent signals

$$\tilde{f}(\mathcal{F},\omega,t) = \sum_{I_H} P_{I_H}(\mathcal{F},\omega,t) f_{I_H}(\omega)$$

> Relative effective scattering strength

$$\tilde{a}(\mathcal{F},\omega) = \frac{1}{\left\{f_{H}^{0}\right\}^{2}} \int_{-\infty}^{\infty} dt \, g(t) \left|\tilde{f}(\mathcal{F},\omega,t)\right|^{2}$$

> XATOM describes dynamical behaviors  $P_{I_H}(\mathcal{F}, \omega, t)$  and computes  $f_{I_H}(\omega)$  for every single  $I_H$ 





# Fluctuation effect on scattering strength

Generalized KH equation: not only for phasing but also for refinement



# MAD at high x-ray intensity



- > calculated by XATOM
- different ionization mechanism before and after the edge
- > contrast at different wavelengths
- contrast at different fluences, too
- easier to vary fluence than wavelength

Son, Chapman & Santra, *Phys. Rev. Lett.* **107**, 218102 (2011).





# Towards high-intensity phasing (HIP)



- > exploit electronic radiation damage to S atoms ( $\sigma_{s} > \sigma_{light atoms}$ )
- > simulated datasets of Cathepsin B including ionization for all atoms
- > phased by the RIP workflow (High-intensity RIP)





## Case study: Gd-derivatized lysozyme







Sang-Kil Son | Phasing with electronic radiation damage at high x-ray intensity | January 16, 2015 | 14 / 20

# Gd is really heavy

- > Gd-lysozyme diffraction measured at LCLS CXI (8.5 keV)
- > Gd: 64 electrons
- XATOM calculation
  - ionization dynamics:  $P_{I_H}(t)$  for every  $I_H$  (N of  $I_H > 400$ M)
  - anomalous scattering calculation:  $f_q(\omega)$  for every q (N of q = 64)

$$\tilde{f}(\mathbf{Q}, \mathcal{F}, \omega, t) = \sum_{q} P_q(\mathcal{F}, \omega, t) \left[ f_q^0(\mathbf{Q}) + f_q'(\omega) + i f_q''(\omega) \right]$$

Effective scattering strength for Gd

$$f_{\text{eff}} = \sqrt{\frac{\int d^3x \int dt \mathcal{F}(\mathbf{x}) g(t) |\tilde{f}(\mathbf{Q}, \mathcal{F}, \omega, t)|^2}{\int d^3x \int dt \mathcal{F}(\mathbf{x}) g(t)}}$$

 $\mathcal{F}(\mathbf{x})$ : spatial profile, g(t): temporal profile of the x-ray beam





# **Scattering strength differences**



**Experimental analysis** 

- From the difference density map: 8.8~12e<sup>-</sup>
- From anomalous refinement (f' and f''): 5e<sup>-</sup>





# **List of speculations**

#### based on an atomic model

- relativistic treatment for heavy atoms
- molecular environment
- Iocal plasma environment / collisional ionization
- > calibration of x-ray beam parameters
- self-gating of the Bragg peaks
- ionization-induced fluctuation at high x-ray intensity
- > crystal size
- scaling procedure

Galli et al., (submitted).

Theoretical estimation: 11~25e<sup>-</sup>

Experimental analysis: 5~12e<sup>-</sup>





## **Outlook: new developments**

#### > XMDYN (Zoltan Jurek)

- atomic processes by XATOM
- molecular dynamics by XMDYN
- C<sub>60</sub> at LCLS

SCIENCE

Ar cluster at SACLA



Murphy *et al.*, *Nature Commun.* **5**, 4281 (2014).

#### > XMOLECULE (Yajiang Hao, Ludger Inhester, Kota Hanasaki)

- detailed description on molecular environment
- molecular Auger effect and charge redistribution





Electronic radiation damage: unavoidable at high x-ray intensity

- XATOM describes multiphoton multiple ionization dynamics of individual atoms; tested by LCLS and SACLA experiments
- Seneralized Karle-Hendrickson equation: a key formula for phasing at high x-ray intensity
- > High-Intensity Phasing (HIP): new opportunities for solving the phase problem in nanocrystallography with XFELs





## **Acknowledgments**

- CFEL-DESY Theory, DESY, Germany: Zoltan Jurek, Yajiang Hao, Ludger Inhester, Kota Hanasaki
- > CFEL Coherent Imaging, DESY, Germany: Thomas White, Anton Barty
- > EMBL Grenoble, France: Max Nanao
- Max Planck Institute for Medical Research, Heidelberg, Germany: Thomas Barends, Sabine Botha, Bruce Doak, Karol Nass, Robert Schoeman, Ilme Schlichting
- > SLAC, USA: Sébastien Boutet
- > Uppsala University, Sweden: Carl Caleman, Nicuşor Tîmneanu





## **Ultrafast X-ray Summer School 2015**



#### June 22–25, 2015 CFEL, DESY, Hamburg, Germany http://conferences.cfel.de/uxss\_2015/ (will open in February)

Markus Gühr<br/>Giorgio Margaritondo<br/>David ReisThomas White<br/>Wilfried Wurth<br/>Linda Young<br/>Ulf Zastrau



